Q-STAR TEST AND SOURCEIII ANNOUNCE A STRATEGIC PARTNERSHIP TO HELP FURTHER REDUCE TEST COSTS AND ENHANCE PRODUCT QUALITY

Brugge, Belgium / El Dorado Hills, CA, USA — *February 22, 2008* — Q-Star Test nv., the premier supplier of advanced high speed and high accurate IDD test and measurement solutions, and Source III, Inc., a leading developer of test conversion and verification programs, announce a strategic partnership and collaboration to enable reducing test engineering efforts, improved test validation and faster test conversion for enhanced chip quality.

Q-Star Test offers IDDX and ISSX monitor solutions, supporting true IDDQ, delta IDDQ, IDDT and analog IDD and the complementary ISSX test strategies applicable to digital, analog, and mixed signal circuits. Q-Star Test's measurement hardware is ATE independent and outperforms other available ATE related IDD test hardware by at least a factor of 100 (with respect to measurement speed and accuracy). The hardware solutions are complemented with application and test strategy related consulting and training services.

Source III Simulation and Test Data Management tools provide for quick and easy creation of simulation vector data (VGEN), translation between over 30 popular simulator/ATPG formats and numerous tester formats (VTRAN), and verification/analysis of simulation data files (VCAP). All Source III products are supported on Sun Solaris, HPUX, and Linux (32 and 64-bit) platforms.

The partnership and collaboration targets the automated insertion of Q-Star Test IXXX module control using Source III's VTRAN tool into the test pattern data either when generating a test program starting from ATPG data or when translating from one ATE format to another.

Q-Star Test and Source III are happy to announce that as a first result of the cooperation a push-button automated WGL based VTRAN flow has been established and validated by customers that allows automated insertion of Q-Star Test module control into the test pattern data, resulting in a ready to use test program. Further work is focusing on setting up a similar STIL based flow which will be available within 30 days.

"The realization of the automated WGL based VTRAN module control insertion flow drastically reduces test engineering efforts when using Q-Star Test products and brings a high-level, easy to use push-button solution, eliminating human errors and related test pattern debugging efforts." said Dr. Hans Manhaeve, Q Star Test's President and CEO. "In addition, such an approach is platform independent and paves the way to ensuring high quality testing at minimal cost."

"We see this partnership as a tremendous opportunity to help the semiconductor industry find effective ways to control test costs. Adding this functionality to our VTRAN tool

helps our customers to shorten engineering time and easily endorse advanced I_{DDX} and I_{SSX} test methodologies" said John Cosley, Source III's President & CEO. "From this perspective, the cooperation between Source III and Q-Star Test provides solutions that overcome issues and challenges surrounding advanced semiconductor test."

The partnership between Q-Star Test and Source III will allow customers to benefit from the combination of products and services offered. By combining Source III's software solutions with Q-Star Test's measurement hardware, an easy route toward the implementation of a (supply) current based test strategy applicable in a production test environment is created. Meanwhile, customers will benefit from a reduction of test engineering efforts, test program debug time, test time and costs, and an improvement of product quality. The partnership will also allow Q-Star Test and Source III to reinforce their market position and to provide the semiconductor market with cost effective and powerful soft- and hardware solutions to reduce test time and costs.

About Q-Star Test nv

Q-Star Test is the premier provider of current-based (I_{DD}/I_{SS}) test and measurement solutions. The company offers I_{DDx} and I_{SSx} measurement solutions, supporting true I_{DDQ}, I_{SSQ}, delta I_{DDQ}/ I_{SSQ}, I_{DDT}, and analog I_{DD} test strategies, which apply to digital, analog, and mixed-signal circuits. The company provides standard and customized products and services. Q-Star Test owns several supply current measurement technologies covered by a set of strategic patents. These technologies allow the creation of high-speed, high-accuracy supply current monitors, with the unique characteristic of being virtually transparent to the device under test and the automatic test equipment (ATE). Q-Star Test's worldwide web address is http://www.qstar.be. The company is located at L. Bauwensstraat 20, B-8200 Brugge, Belgium.

About Source III .

Source III was founded in 1980 to provide full custom and semicustom design services, making extensive use of gate array and standard cell design methodologies. During the first 6 years of its existence dozens of custom and semicustom design projects were completed for many large electronics companies.

Source III provides vector file translation services involving the translation of logic simulation data files and ATPG-generated files to vector formats either for physical device testers or for other logic simulators and analysis tools. We support translations between more than 30 formats.

The current focus of the company is providing CAE tools which aid the designer in the data-intensive aspects of design/simulation/test. This includes stimulus generation (VGEN), simulation/ATPG data translation (VTRAN and test option), and simulation data

verification/analysis (VCAP). All areas in which growing needs are not being met by the major CAE vendors. Source III' worldwide web address is www.sourceiii.com The company is located at 3941 Park Drive, #20-342, El Dorado Hills, CA 95762

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ACRONYMS AND DEFINITIONS:

ATE:	Automatic Test Equipment
ATPG:	Automatic Test Pattern Generation
DFT:	Design-for-Test
EDA:	Electronic Design Automation
I_{DD}:	Device supply current
I_{DDQ}:	Quiescent supply current
I_{SS}:	Device ground current
I_{SSQ}:	Quiescent ground current
I_{DDT}:	Transient supply current – switching current
WGL	Waveform Generation Language
STIL	Standard Test Interface Language (IEEE Std.1450-1999)